## An Advanced Behavioral Buffer Model With Over-Clocking Solution

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1. SPICE Model and Behavioral Buffer Model

2. Over-Clocking Problem in IBIS

3. Proposed Solution and Results





1. SPICE Model and Behavioral Buffer Model

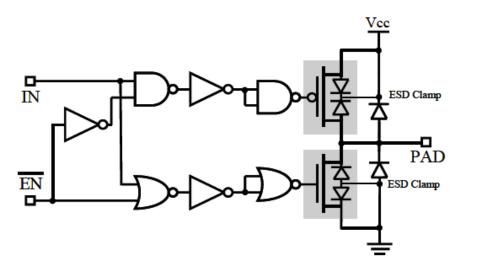
2. Over-Clocking Problem in IBIS

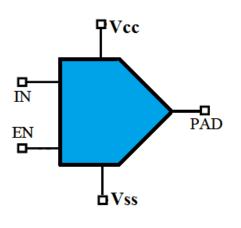
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### SPICE Model and Behavioral Buffer Model

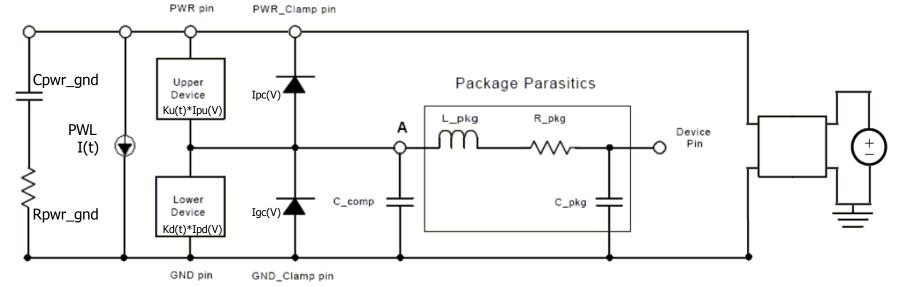
- SPICE model is a circuit netlist at transistor level, it contains detailed information about the circuit design and process parameters.
- Behavioral model is a black box model with certain terminal information, which is obtained from measurement or extracted from SPICE model. IBIS is a widely adopted standard behavioral model.





## A Simple Schematic for IBIS Model

- The non-linear behavior of pullup, pulldown and clamps are described by I/V tables, and modeled as voltage controlled current sources.
- The transition behavior is described by the V/T table of the rising/falling waveforms under specified loading condition. And they are used to derive/scale instantaneous value of the I/V curves.
- Other important parasitic elements
- IBIS, as a behavioral model, does not contain transistor equation, some of the physics and detailed response may not exist in a simple model, hence the issue that will be discussed next.





1. SPICE Model and Behavioral Buffer Model

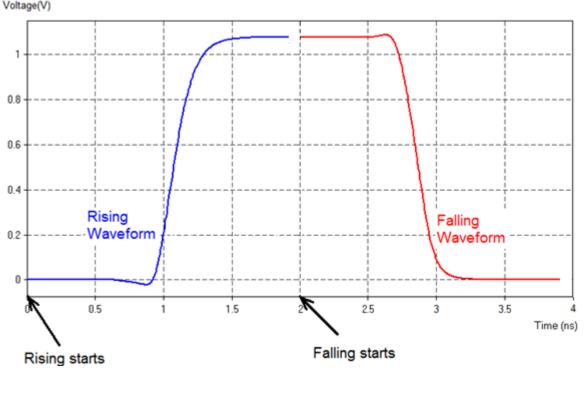
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#### **Understand the Over-Clocking**

 Normal operating, the input data bit width > the time range of the IBIS rising and falling waveform.

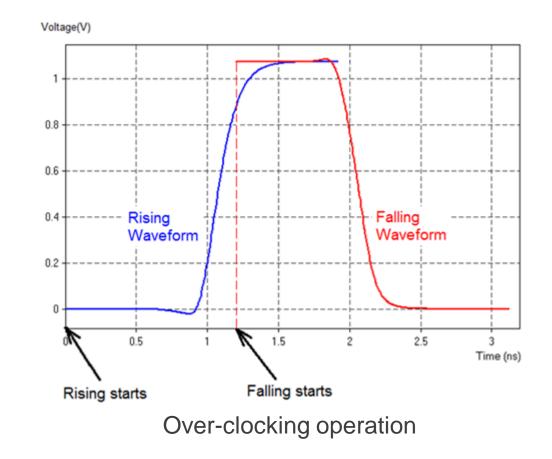


#### Normal operation



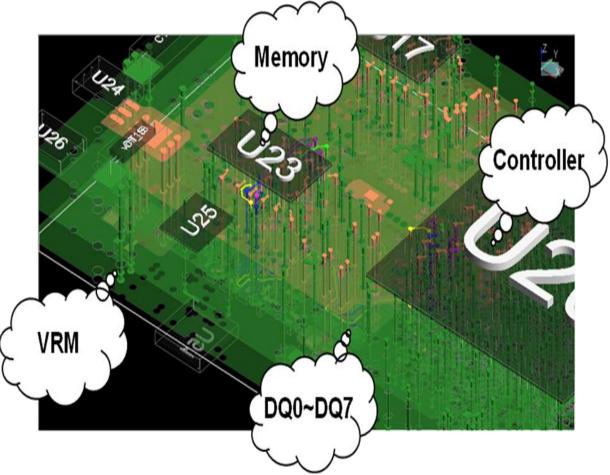
### Understand the Over-Clocking (cont.)

- If the input signal bit width is smaller than the time range of the IBIS waveforms, the next transition is triggered before this transition is finished.
- The behavior of the IBIS simulator may be unpredictable.
- Google "IBIS Overclocking" to find out more about this issue discussion since 2002



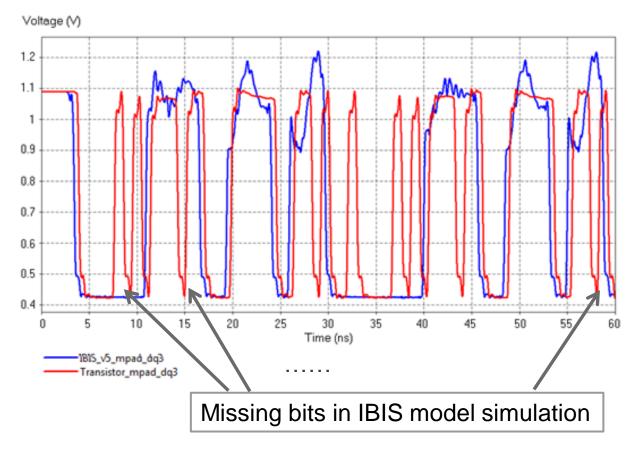
## Simulation Problem Is Shown with A DDR3 SSO Test Case

8 signal nets + 1 power nets + 1 ground net from a real PCB design. Bit width is 1ns, the pattern is 0001010111100110110011010010



### **Problematic Results from Over-Clocking**

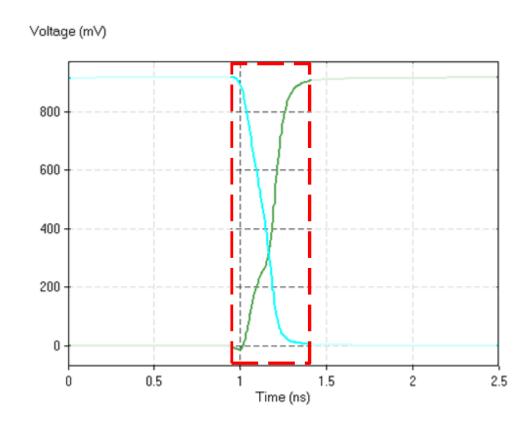
- A test case operating over-clocking
- Simulation results show missing bits





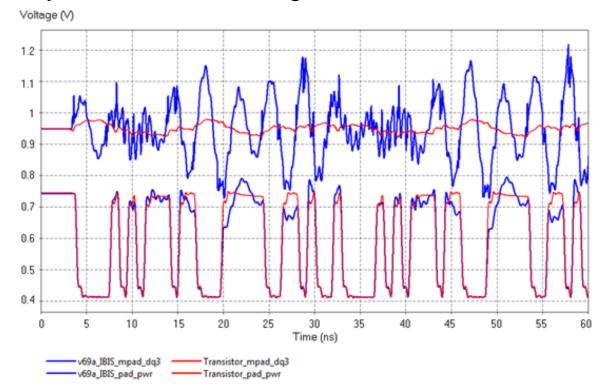
## Existing Solution to Solve Over-Clocking Problem

- V/T curve windowing by cutting the initial delay and the flat tail of the rising/falling waveforms of IBIS model to make the time range shorter
- The windowing can be done either in IBIS model creation or simulation tools



## Simulation Results with V/T Windowing

- The missing bits resolved
- Therefore, simulator with proper V/T windowing scheme should automatically handle overclocking issue in IBIS 4.2 model

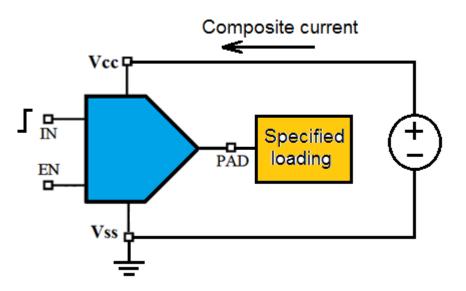


 However, voltage on power net mismatches between transistor model and IBIS model due to the dynamic power noise not modeled.



#### New Challenge of Over-Clocking with Composite Current

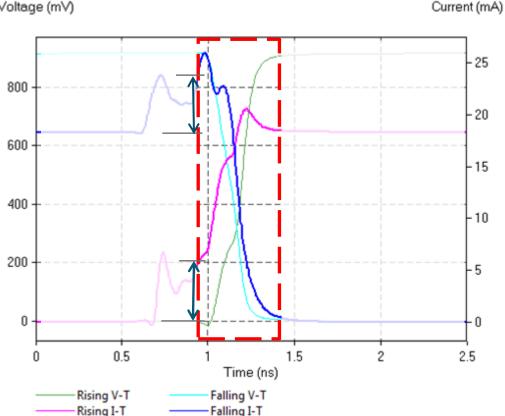
- To accurate model the power-aware buffer model, the composite currents (I/T) are introduced in IBIS V5.0 to give the current waveforms on power pin.
- The I/T data must be time correlated with the waveform
  V/T data which are extracted from pad pin.
- The composite current includes the contribution of the pre-driver and all the other on-die P/G paths. It has wider time range than V/T waveform.



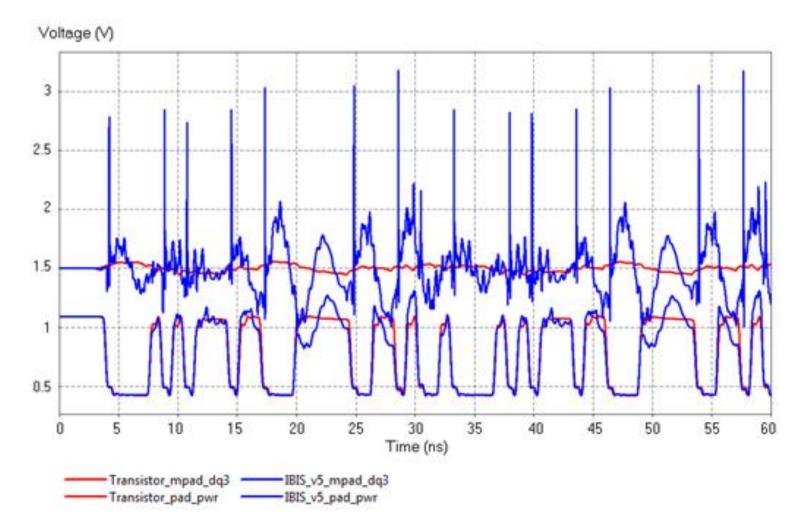
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## Windowing with Composite Current

- Now both V/T and I/T need<sub>Voltage (mV)</sub> to be windowed.
- Choosing window based on wider I/T curve will not help, since over-clocking solution requires narrow timing window for higher frequency operation.
- Still choosing a window based on V/T will cut the composite current incomplete which will form a sharp step current.



#### The Sharp Step of Incomplete Composite Current Causes Unreal Large Voltage Spikes



### **Observation of This New Challenge**

- With the addition of composite current (I/T) in IBIS 5.0, old windowing technique (V/T based) in IBIS simulator need to be improved, and can't be directly applied to I/T data to solve over-clocking issue.
- With IBIS 5.0 models become increasingly popular in the last few years, there are more awareness and discussion of this issue.
- A solution was developed by us two years ago to tackle this challenge.





1. SPICE Model and Behavioral Buffer Model

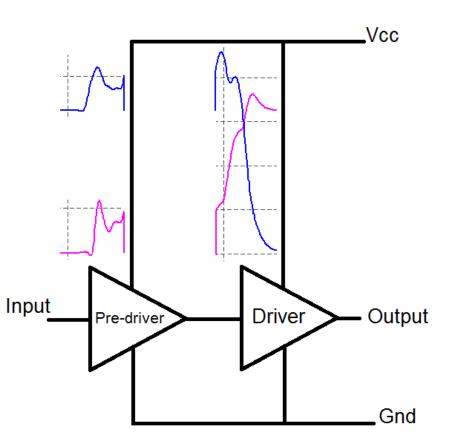
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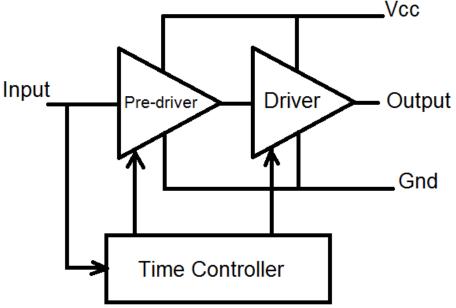
## Key Point of Advanced Over-Clocking Solution

- Using the V/T waveform windowing
- Adding one stage to the existing driver to keep the pre-driver behavior for the buffer switching delay and power current
- Taking the composite current compensation into two parts:
  - Driver contribution
  - Pre-driver contribution



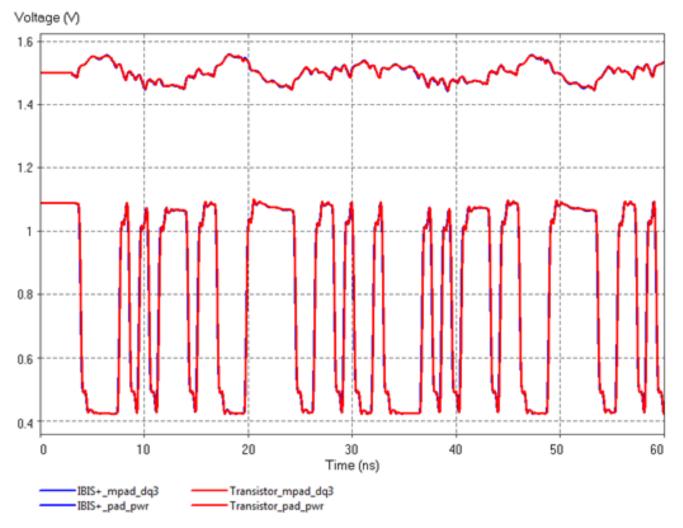
## Implementing the Proposed Over-Clocking Solution

- The proposed over-clocking solution can be implemented into an advanced IBIS model, which is a SPICE netlist with <u>integrated model</u> <u>data and simulation algorithm</u>.
- The proposed over-clocking solution can also be implemented into an advanced IBIS simulator to automatically handle the windowing of both V/T and I/T data.





## Simulation results with Advanced Over-Clocking Solution



## **Simulation Performance Summary**

- Very good correlation between IBIS and the original transistor model for real SSO simulation, both signals and power/ground waveforms match very well, even under over-clocking scenario.
- The 60ns simulation time is based on 32 clock cycles of data input.
- It takes 54 minutes for original transistor level SPICE model.
- It takes 55 seconds for the behavioral model with the advanced over-clocking solution.
- Note: HSPICE is used to run the simulations for all the models, including the advanced IBIS model with over-clocking solution.

#### Conclusion

- Power-aware buffer model generation has been implemented for IBIS 5.0 standard. When used in highspeed power-aware SSO simulations, user often has to deal with IBIS over-clocking issues.
- With the proposed algorithm for handling composite currents under over-clocking situation, more advanced model shows significant accuracy improvement compared with traditional IBIS models, while keeping the fast simulation advantages of IBIS.
- Advances in IBIS standard, together with advances in modeling and simulation algorithms, continue to make this behavioral model technique a great and practical engineering approach for high-speed design.

#### References

- [1] Perivand F. Tchrani, Yuzhe Chen, Jiayuan Fang, "Extraction of Transient Behavioral Model of Digital I/O Buffers from IBIS", 46th IEEE Electronic Components & Technology Conference, Orlando, May 28-31, 1996, pp 1009-1015.
- [2] Ying Wang and Han Ngee Tan, "The Development of Analog SPICE Behavioral Model Based on IBIS Model", Proceedings of the Ninth Great Lakes Symposium on VLSI, March 1999.
- [3] Sam Chitwood, Raymond Y. Chen, Jiayuan Fang, "An Initial Case Study for BIRD95 - Enhancing IBIS for SSO Power Integrity Simulation", IBIS Summit DesignCon, January 2005.
- [4] Raymond Y. Chen, "Recent Development of IBIS and Related EDA Technologies", Sigrity Annual User Forum, May 24, 2011

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